



US00D836211S

(12) **United States Design Patent** (10) **Patent No.:** **US D836,211 S**  
**Ito et al.** (45) **Date of Patent:** **\*\* Dec. 18, 2018**

(54) **SUBSTRATE FOR SPECTROSCOPIC ANALYSIS**

9/54; B01L 9/06; B01L 9/52; B01L 9/543; B01L 9/00; B01L 3/5085; B01L 3/5027

(71) Applicant: **HAMAMATSU PHOTONICS K.K.**,  
Shizuoka (JP)

See application file for complete search history.

(72) Inventors: **Masashi Ito**, Hamamatsu (JP);  
**Katsumi Shibayama**, Hamamatsu (JP);  
**Kazuto Ofuji**, Hamamatsu (JP);  
**Yoshihiro Maruyama**, Hamamatsu  
(JP); **Mitsuhiko Ito**, Hamamatsu (JP)

(56) **References Cited**

U.S. PATENT DOCUMENTS

3,736,042	A *	5/1973	Markovits .....	G01N 1/28 359/398
D273,898	S *	5/1984	Valencia .....	D24/225
D274,261	S *	6/1984	Valencia .....	D24/225
4,761,381	A	8/1988	Blatt et al.	
D320,269	S	9/1991	Hammond	
5,784,193	A *	7/1998	Ferguson .....	G02B 21/34 359/396
5,812,312	A *	9/1998	Lorincz .....	G01N 1/30 359/396
D500,142	S	12/2004	Crisanti et al.	
D531,321	S	10/2006	Godfrey et al.	

(73) Assignee: **HAMAMATSU PHOTONICS K.K.**,  
Hamamatsu-shi, Shizuoka (JP)

(\*\*) Term: **15 Years**

(21) Appl. No.: **35/502,699**

(22) Filed: **Sep. 30, 2016**

(80) **Hague Agreement Data**

Int. Filing Date: **Sep. 30, 2016**  
Int. Reg. No.: **DM/092883**  
Int. Reg. Date: **Sep. 30, 2016**  
Int. Reg. Pub. Date: **Mar. 31, 2017**

*Primary Examiner* — Richard E Chilcot

(57) **CLAIM**

The ornamental design for a substrate for spectroscopic analysis, as shown and described.

(30) **Foreign Application Priority Data**

Apr. 27, 2016 (JP) ..... 2016-009316

(51) **LOC (11) Cl.** ..... **24-02**

(52) **U.S. Cl.**  
USPC ..... **D24/225**  
CPC ..... **G01N 1/28** (2013.01)

(58) **Field of Classification Search**

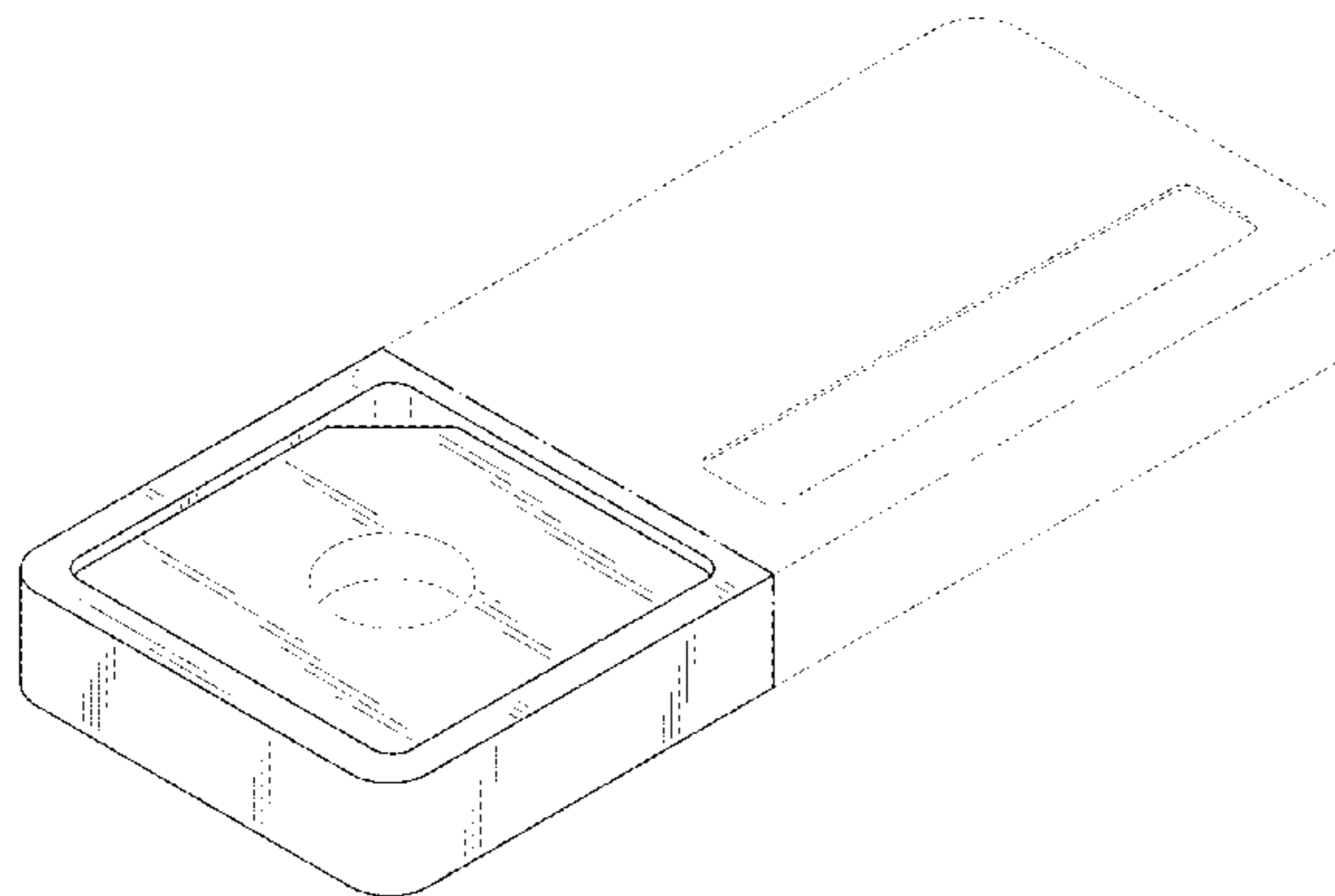
USPC ..... D24/216, 222–226, 231, 232, 169;  
D10/80, 81; 422/68.1, 69, 547;  
435/283.3, 288.4, 289.1, 283.1, 288.2,  
435/288.5; 436/44, 46  
CPC ..... B01J 19/0046; B01J 2219/00596; G01N  
1/405; G01N 35/00009; G01N 1/312;  
B01L 2300/0816; B01L 2400/0406; B01L

**DESCRIPTION**

- 1. Substrate for spectroscopic analysis
- 1.1 : Perspective
- 1.2 : Front
- 1.3 : Back
- 1.4 : Top
- 1.5 : Bottom
- 1.6 : Left
- 1.7 : Right
- 1.8 : SECTIONAL VIEW
- 1.9 : SECTIONAL VIEW
- 1.10 : PERSPECTIVE VIEW WITHOUT THE COVER PART

The broken line showing the substrate for spectroscopic analysis is for the purpose of illustrating environmental structure and forms no part of the claimed design.

(Continued)



The dot-dash broken lines define the bounds of the claimed design and form no part thereof.

**1 Claim, 10 Drawing Sheets**

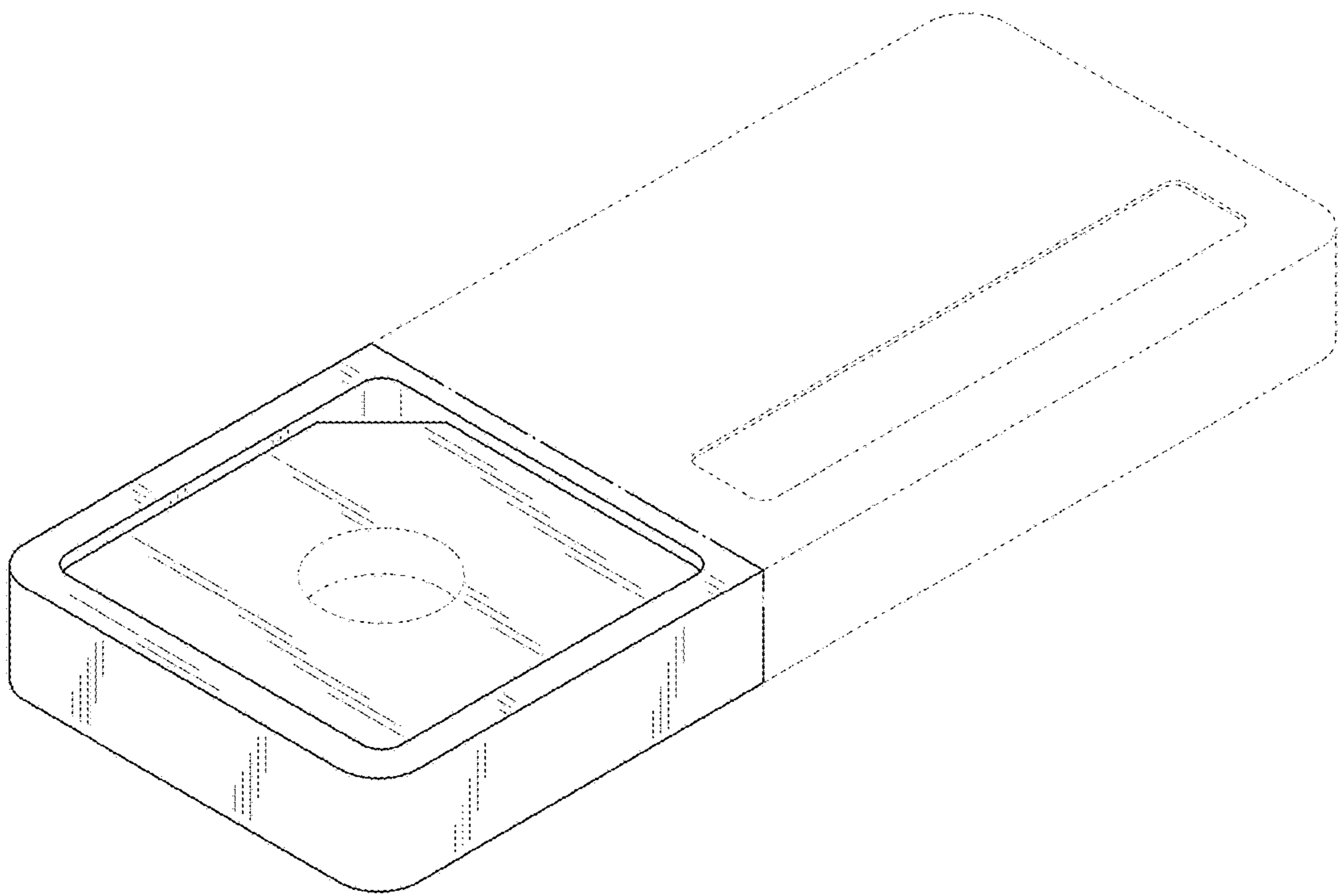
(56) **References Cited**

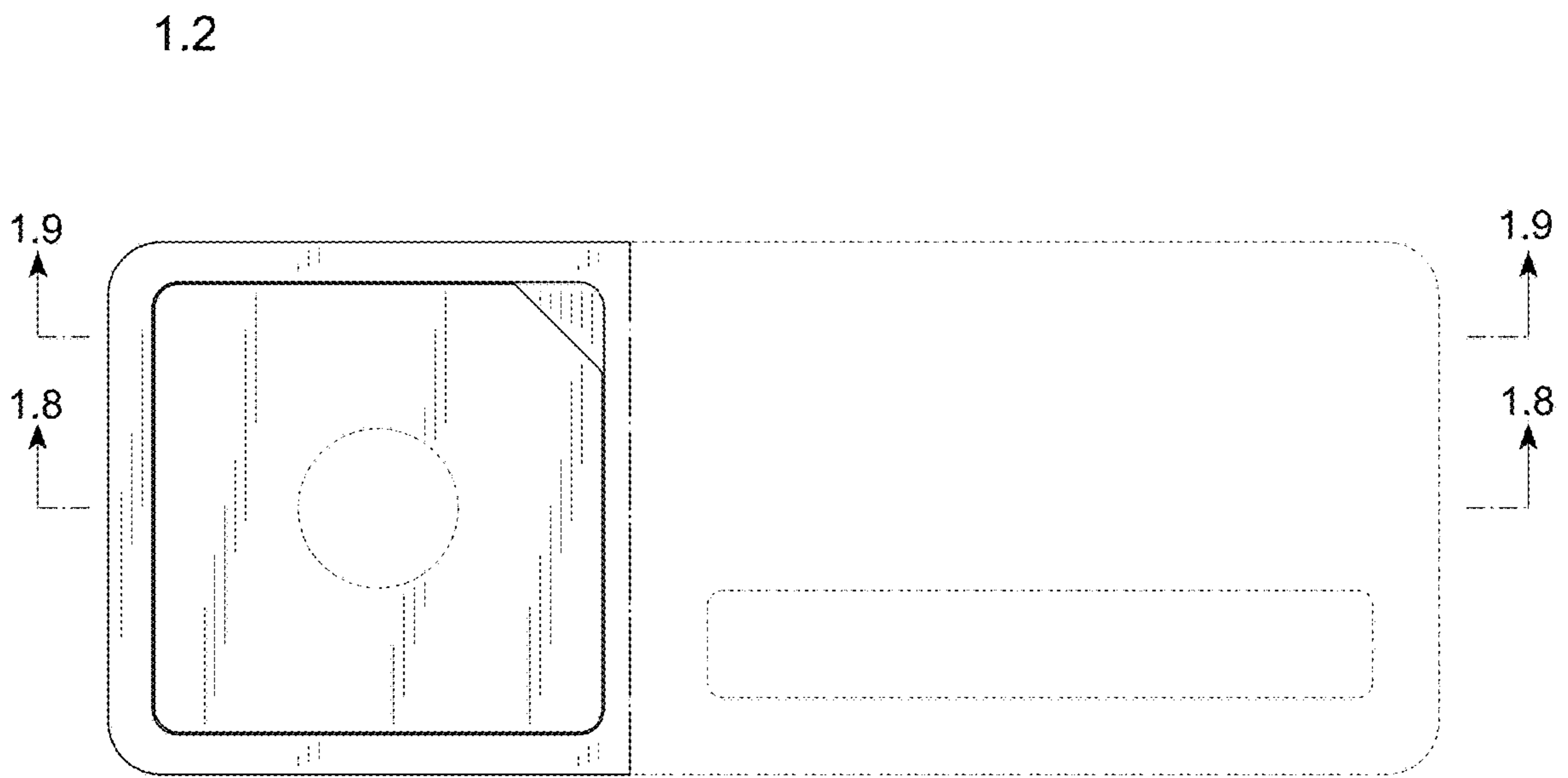
U.S. PATENT DOCUMENTS

D683,045	S	*	5/2013	Domack	.....	D24/225
D692,578	S		10/2013	Kikuhara et al.		
D702,364	S	*	4/2014	Iqbal	.....	D24/225
D733,911	S	*	7/2015	Ito	.....	D24/225
D733,912	S	*	7/2015	Ito	.....	D24/225
D733,913	S	*	7/2015	Ito	.....	D24/225
D735,877	S	*	8/2015	Chang	.....	D24/216
D739,954	S	*	9/2015	Ito	.....	D24/225
D740,439	S	*	10/2015	Ito	.....	D24/225
D740,440	S	*	10/2015	Ito	.....	D24/225
D750,799	S	*	3/2016	Ito	.....	D24/225
D750,800	S	*	3/2016	Ito	.....	D24/225
D754,871	S	*	4/2016	Morrell-Falvey	.....	D24/225
2005/0237607	A1	*	10/2005	Tenney	.....	G01N 1/2813 359/392

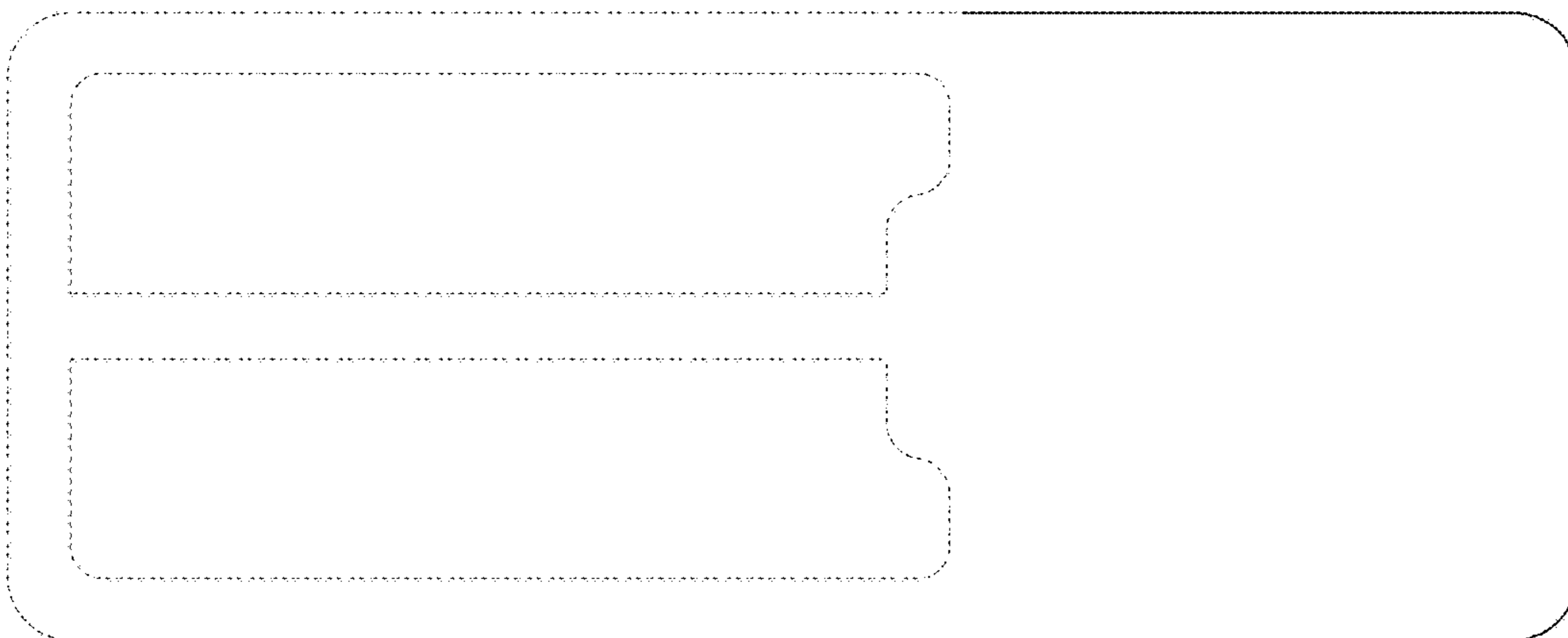
\* cited by examiner

1.1

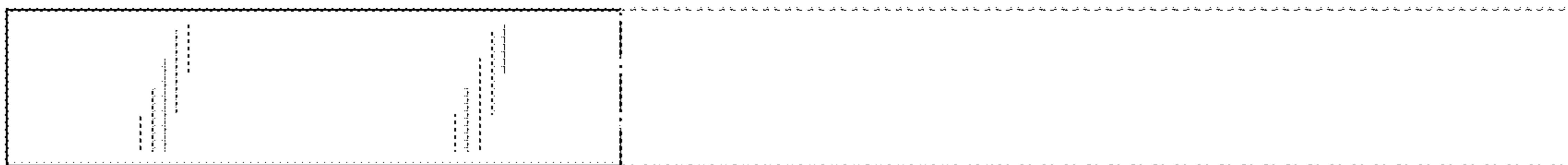




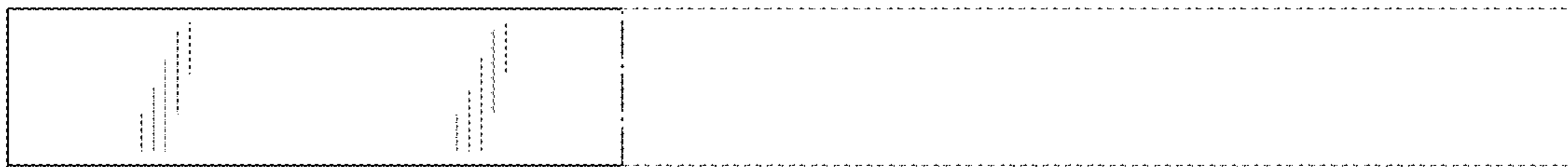
1.3



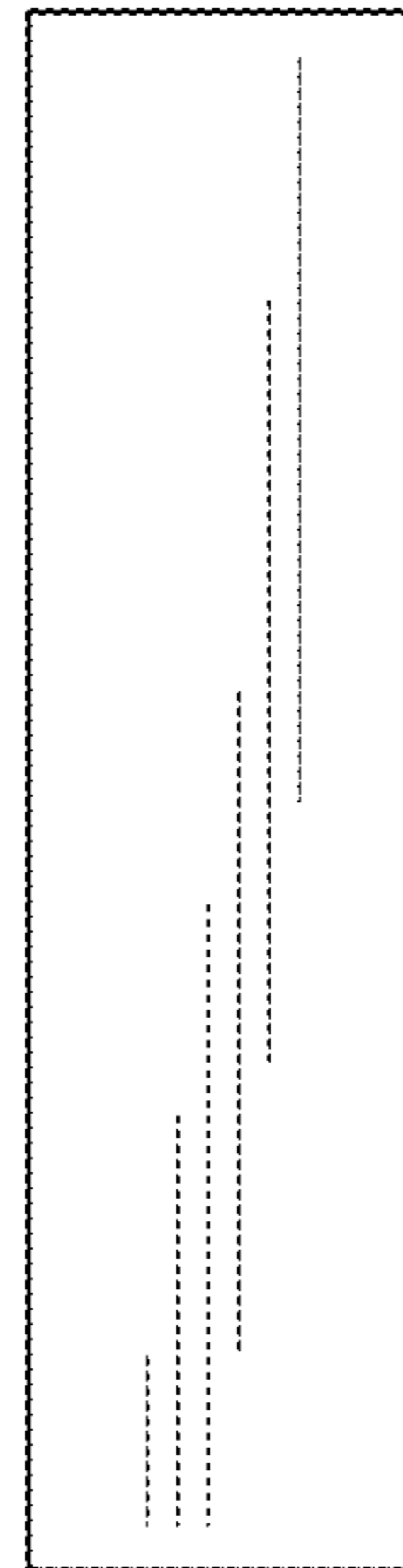
1.4



1.5

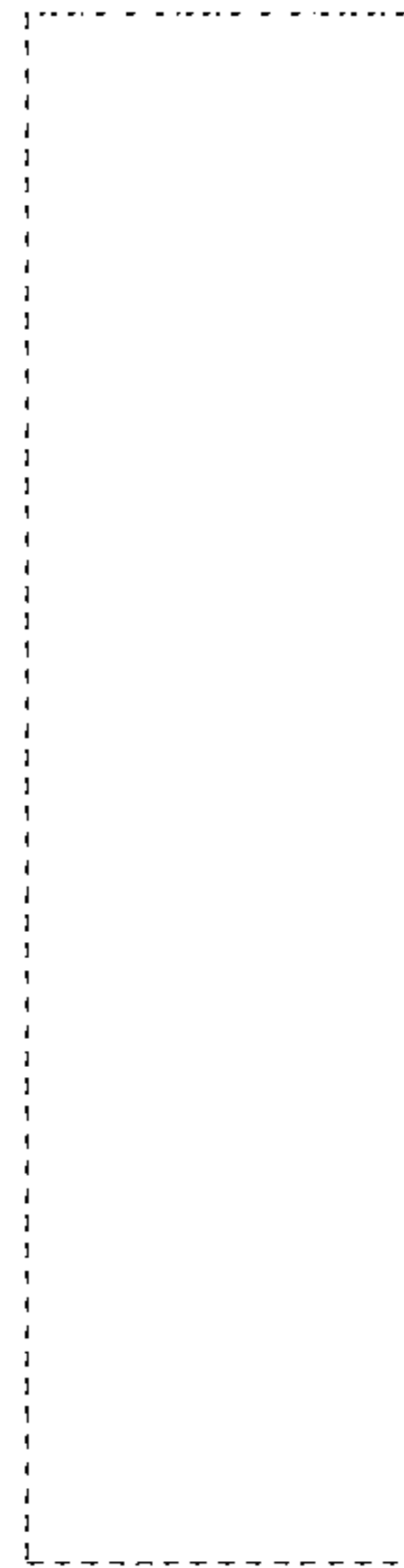


1.6

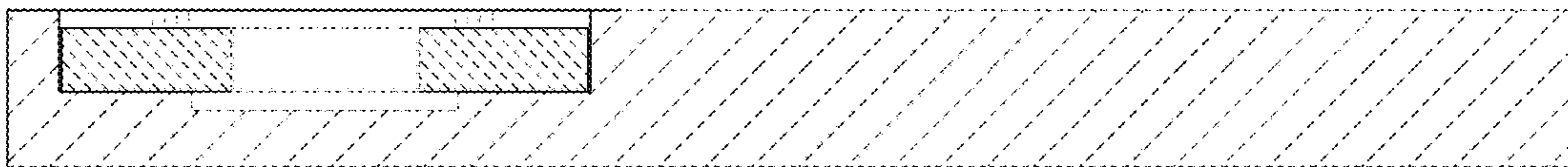




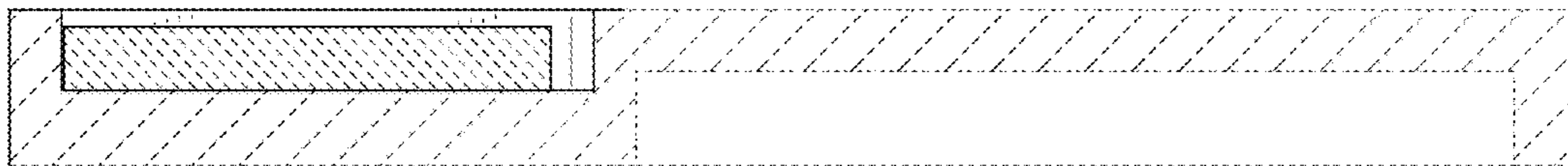
**1.7**



1.8



1.9



1.10

